

Claim 54 (New): A probe card designed by an automated system, said system comprising:

- a server connectable to a network;
- an application operable with said server to provide functions comprising:
  - receiving over said network from said prospective customer information describing a wafer to be tested;
  - generating from said information-a verification package comprising a proposed design of said probe card for testing said wafer; and
  - communicating over said network with said prospective customer regarding the acceptability of said proposed probe card design.

Claim 55 (New): The probe card of Claim 54, wherein said application further provides the function of providing a graphical interface for use by said prospective customer to enable the input of said information describing a wafer to be tested.

Claim 56 (New): The probe card of Claim 55, wherein said graphical interface further comprises at least one Web page.

Claim 57 (New): The probe card of Claim 54, wherein said application further provides the function of accepting an order from said prospective customer to manufacture said proposed probe card design.

Claim 58 (New): The probe card of Claim 54, wherein said application further provides the function of verifying said proposed probe card design.

Claim 59 (New): The probe card of Claim 54, wherein said verification package further comprises drawings of said proposed probe card design.

Claim 60 (New): The probe card of Claim 54, wherein said communicating function further comprises notifying said prospective customer of proposed modifications to said proposed probe card design.